

Notice of References Cited

Application/Control No.

09/196,136

Applicant(s)/Patent Under

Reexamination

OHBAYASHI, SHIGEKI

Examiner

Guy J. Lamarre, P.E.

Art Unit

2133

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,703,510	12-1997	Iketani et al.	327/143
	B	US-			
	C	US-			
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	F	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ruparel et al. (A vertically integrated test methodology based on JTAG IEEE 1149.1 Standard Interface; IEEE, 27 Sept. 1991)
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

FORM PTO-892		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		SERIAL NO. 09/196,136	GROUP ART UNIT 2133	ATTACHMENT TO PAPER NO.	2
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